

Application/Control No.	Applicant(s)/Patent under Reexamination
10/537,311	CHO ET AL.
Examiner	Art Unit
The y Dueng	2753

	SEARCHED		
Class	Subclass	Date	Examiner
165	4	1/5/2006	TD
	6	1/5/2006	TD
	8	1/5/2006	TD
	9.4	1/5/2006	TD
	10	1/5/2006	TD
	66	1/5/2006	TD
	85	1/5/2006	TD
	86	1/5/2006	TD
	122	1/5/2006	TD

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
Text search (See attached)	1/5/2006	TD			
Inventor name search (See attached)	1/5/2006	TD			
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